

W66 N220 Commerce Court ● Cedarburg, WI 53012 ● USA Phone: 262.375.4400 ● Fax: 262.375.4248

www.lsr.com

# TEST REPORT # 311094 LSR Job #: C-1148

Compliance Testing of:

SiFlex-02 HP

With Bowtie Antenna

Test Date(s):

March 17, 18, 21, April 8, May 12, 2011

Prepared For:

LS Research, LLC

Attn: Bill Steinike

W66 N220 Commerce Ct Cedarburg, WI 53012

In accordance with:

Federal Communications Commission (FCC)
Part 15, Subpart C, Section 15.247
Industry Canada (IC) RSS 210 Annex 8
Digital Modulation Transmitters (DTS) Operating in the
Frequency Band 902 MHz – 928 MHz

This Test Report is issued under the Authority of:

Peter Feilen, EMC Engineer

Signature: Letter Film Date: 5/26/2011

Test Report Reviewed by:

Aidi Zainal, EMC Engineer

Signature: Date: 5/12/2011

Tested by: Peter Feilen, EMC Engineer

Signature: leter Film Date: 05/12/2011

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# EXHIBIT 1. INTRODUCTION

# 1.1 <u>SCOPE</u>

References:	FCC Part 15, Subpart C, Section 15.247 and 15.209	
	FCC Part 2, Section 2.1043 paragraph (b)1.	
	RSS GEN and RSS 210 Annex 8	
Title:	FCC: Telecommunication – Code of Federal Regulations,	
	CFR 47, Part 15.	
	IC: Low-power License-exempt Radio-communication Devices	
	(All Frequency Bands): Category I Equipment	
Purpose of Test:	To gain FCC and IC Certification Authorization for Low-	
	Power License-Exempt Transmitters.	
Test Procedures:	Both conducted and radiated emissions measurements	
	were conducted in accordance with American National	
	Standards Institute ANSI C63.4 – American National	
	Standard for Methods of Measurement of Radio-Noise	
	Emissions from Low-Voltage Electrical and Electronic	
	Equipment in the Range of 9 kHz to 40 GHz.	
Environmental Classification:	Commercial, Industrial or Business	
	Residential	

# 1.2 NORMATIVE REFERENCES

Publication	Year	Title
47 CFR, Parts 0-15 (FCC)	2008 Oct	Code of Federal Regulations - Telecommunications
RSS 210 Annex 8	2010 Dec	Low-power License-exempt Radio- communication Devices (All Frequency Bands): Category I Equipment
ANSI C63.4	2003	American National Standard for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz.
CISPR 16-1-1	2006-03 A1: 2006-09 A2: 2007-07	Specification for radio disturbance and immunity measuring apparatus and methods.  Part 1-1: Measuring Apparatus.
CISPR 16-2-1	2003 A1: 2004-04 A2: 2007-07	Specification for radio disturbance and immunity measuring apparatus and methods. Part 201: Conducted disturbance measurement.
FCC Public Notice DA 00-1407	2000	Part 15 Unlicensed Modular Transmitter Approval
FCC ET Docket No. 99-231	2002	Amendment to FCC Part 15 of the Commission's Rules Regarding Spread Spectrum Devices.
FCC Procedures	2007	Measurement of Digital Transmission Systems operating under Section 15.247.

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### 1.3 LS Research, LLC TEST FACILITY

LS Research, LLC is accredited by A2LA (American Association for Laboratory Accreditation) to conform to ISO/IEC 17025, 2005 "General Requirements for the Competence of Calibration and Testing Laboratories".

LS Research, LLC's scope of accreditation includes all test methods listed herein, unless otherwise noted. A copy of the accreditation may be accessed on our web site: <a href="www.lsr.com">www.lsr.com</a>. Accreditation status can be verified at A2LA's web site: <a href="www.a2la2.net">www.a2la2.net</a>.

### 1.4 **LOCATION OF TESTING**

All testing was performed at LS Research, LLC, W66 N220 Commerce Court, Cedarburg, Wisconsin, 53012 USA, utilizing the facilities listed below, unless otherwise noted.

List of Facilities Located at LS Research, LLC:

- Compact Chamber
- Semi-Anechoic Chamber
- Open Area Test Site (OATS)

### 1.5 <u>TEST EQUIPMENT UTILIZED</u>

A complete list of equipment utilized in testing is provided in Appendix A of this test report. Calibration dates are indicated in Appendix A. All test equipment is calibrated in accordance with A2LA standards.

Note: Data presented is dated more than 1 year old. Data has been re-reviewed and the testing in the report is valid.

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# **EXHIBIT 2. PERFORMANCE ASSESSMENT**

### 2.1 **CLIENT INFORMATION**

Manufacturer Name:	LS Research, LLC
Address:	W66 N220 Commerce Ct
Contact Name:	Bill Steinike

### 2.2 EQUIPMENT UNDER TEST (EUT) INFORMATION

The following information has been supplied by the applicant.

Product Name:	SiFlex-02 HP
Model Number:	SiFLEX02-HP
Serial Number:	00:25:CA:08:00:00:01

# 2.3 ASSOCIATED ANTENNA DESCRIPTION

A custom bowtie-PCB antenna with a gain of +3.7 dBi was connected to both ports of the radio board. The antenna connects to the board via U.FL to SMA cables.

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# 2.4 <u>EUT'S TECHNICAL SPECIFICATIONS</u>

# <u>Additional Information</u>:

EUT Frequency Range (in MHz)	906-924 MHz
ERP RF Power in Watts	
Minimum:	0.295 W
Maximum:	0.646 W
Conducted Output Power (in dBm)	
Minimum:	24.70 dBm
Maximum:	28.14 dBm
Field Strength at 3 meters	131.31 dBuV/m at 3m
Occupied Bandwidth (99% BW)	1.63 MHz
Type of Modulation	BPSK
Emission Designator	1M63G1D
EIRP (in mW)	4055.09 mW
Transmitter Spurious (worst case) at 3 meters	51.7 dBuV/m @ 3m @ 1848 MHz
Receiver Spurious (worst case) at 3 meters	36.5 dBuV/m @ 3m @ 3822 MHz
Frequency Tolerance %, Hz, ppm	Better than 100 ppm
Microprocessor Model # (if applicable)	ATXMEGA256A3
Antenna Information	
Detachable/non-detachable	Detachable
Туре	Dipole
Gain (in dBi)	+3.7 dBi
EUT will be operated under FCC Rule Part(s)	15.247
EUT will be operated under RSS Rule Part(s)	RSS 210, Issue 8 (2010), Section
	Annex 8
Modular Filing	
Portable or Mobile?	Mobile

# **RF Technical Information:**

Type of		SAR Evaluation: Device Used in the Vicinity of the Human Head
Evaluation		SAR Evaluation: Body-worn Device
(check one)	Х	RF Evaluation

If <u>RF Evaluation</u> checked above, test engineer to complete the following:

	Evaluated against exposure limits:   General Public Use  Controlled Use	
•	Duty Cycle used in evaluation: 100 %	
•	Standard used for evaluation: OET Bulletin 65	
•	Measurement Distance: 20 cm	
•	RF Value: 8.5848  V/m A/m W/m <sup>2</sup>	

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### 2.5 PRODUCT DESCRIPTION

The SiFLEX02-HP module is a high performance 900MHz IEEE 802.15.4 radio (AT86RF212 & RF amplifier and low noise amplifier circuit) and microcontroller (ATXMEGA256A3).

### Microcontroller

The Atmel XMEGA A3 is a family of low power, high performance and peripheral rich CMOS 8/16-bit microcontrollers based on the AVR® enhanced RISC architecture. By executing powerful instructions in a single clock cycle, the XMEGA A3 achieves throughputs approaching 1 Million Instructions Per Second (MIPS), thus allowing the system designer to optimize power consumption versus processing speed.

### Radio

The Atmel AT86RF212 is a low-power, low-voltage 800/900 MHz transceiver specially designed for low-cost IEEE 802.15.4, ZigBee™, and high data rate ISM applications. For the sub-1 GHz bands, it supports a low data rate of 40kbps of the IEEE 802.15.4-2003 standard [2] and provides an optional data rate 250kbps using O-QPSK, according to IEEE 802.15.4-2006. Furthermore hardware accelerators improve overall system power efficiency and timing.

The receiver path is based on a low-IF architecture. After channel filtering and down conversion the low-IF signal is sampled and applied to the digital signal processing part. Communication between transmitter and receiver is based on direct sequence spread spectrum with different modulation schemes and spreading codes. The AT86RF212 supports the IEEE 802.15.4-2006 standard mandatory BPSK modulation and optional O-QPSK modulation in the 800 and 900 MHz band. For applications not necessarily targeting IEEE compliant networks the radio transceiver supports proprietary High Data Rate Modes based on O-QPSK.

The AT86RF212 features hardware supported 128 bit security operation. The standalone AES encryption/decryption engine can be accessed in parallel to all PHY operational modes. Configuration of the AT86RF212, reading, and writing of data memory as well as the AES hardware engine are controlled by the SPI interface and additional control signals.

### **RF Front End Module**

The SiFLEX02-HP module contains a high performance RF Front End Module for 900MHz wireless applications. It is capable of +28 dBm output power, providing miles of range in outdoor applications. It also has a built in low noise amplifier for the receiver to increase sensitivity and all antenna switching.

### **Antenna Options**

The SiFLEX02-HP module allows multiple antenna options.

Any antenna terminated by a u.fl

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### EXHIBIT 3. EUT OPERATING CONDITIONS & CONFIGURATIONS DURING TESTS

### 3.1 CLIMATE TEST CONDITIONS

Temperature:	20-25 °C
Humidity:	35-65 % R.H.

### 3.2 APPLICABILITY & SUMMARY OF EMC EMISSION TEST RESULTS

FCC and IC Paragraph	Test Requirements	Compliance (yes/no)
FCC: 15.207 IC: RSS GEN sect. 7.2.2	Power Line Conducted Emissions Measurements	Yes
FCC: 15.247(a)(2) IC: RSS 210 A8.2(a)	6 dB Bandwidth of a Digital Modulation System	Yes
IC : RSS GEN section 4.6.1	20 dB Bandwidth	Yes
FCC: 15.247(b) & 1.1310 IC: RSS 210 A8.4	Maximum Output Power	Yes
FCC: 15.247(i), 1.1307, 1.1310, 2.1091 & 2.1093 IC: RSS 102	RF Exposure Limit	Yes
FCC :15.247(c) IC : RSS 210 A8.5	RF Conducted Spurious Emissions at the Transmitter Antenna Terminal	Yes
FCC: 15.247(d) IC: RSS 210 A8.2(b)	Transmitted Power Spectral Density of a Digital Modulation System	Yes
FCC: 15.247(c), 15.209 & 15.205 IC: RSS 210 A8.2(b), section 2.2, 2.6 and 2.7	Transmitter Radiated Emissions	Yes

The digital circuit portion of the EUT has been tested and verified to comply with FCC Part 15, Subpart B, Class B Digital Devices (RSS GEN and RSS 210 of IC) and the associated Radio Receiver has also been tested and found to comply with Part 15, Subpart B – Radio Receivers (RSS GEN and RSS 210 of IC). The Receiver Test Report is available upon request.

# 3.3 MODIFICATIONS INCORPORATED IN THE EUT FOR COMPLIANCE PURPOSES None Yes (explain below)

### 

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# **EXHIBIT 4. DECLARATION OF CONFORMITY**

The EUT was found to MEET the requirements as described within the specification of FCC Title 47, CFR Part 15.247, and Industry Canada RSS-210, Issue 8 (2010), Section Annex 8 (section 8.2) for a Digital Spread Spectrum (DTS) Transmitter.

### If some emissions are seen to be within 3 dB of their respective limits:

As these levels are within the tolerances of the test equipment and site employed, there is a possibility that this unit, or a similar unit selected out of production may not meet the required limit specification if tested by another agency.

LS Research, LLC certifies that the data contained herein was taken under conditions that meet or exceed the requirements of the test specifications. The results in this Test Report apply only to the item(s) tested on the above-specified dates. Any modifications made to the EUT subsequent to the indicated test date(s) will invalidate the data herein, and void this certification.

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### **EXHIBIT 5. RADIATED EMISSIONS TEST**

### 5.1 Test Setup

The test setup was assembled in accordance with Title 47, CFR FCC Part 15, RSS GEN and ANSI C63.4. The EUT was placed on an 80cm high non-conductive pedestal, centered on a flush mounted 2-meter diameter turntable inside a 3 meter Semi-Anechoic, FCC listed Chamber. The EUT was operated in PRBS mode, with 40 kbps data rate for final testing. Power was provided by a dual-supply bench top supply, providing 3.3VDC to the radio and 4.0VDC to the PA. The unit has the capability to operate on 10 channels, controllable during testing via laptop PC, connected to a programming board and operating LSR software.

The applicable limits apply at a 3 meter distance. Measurements above 4 GHz were performed at a 1.0 meter separation distance. The calculations to determine these limits are detailed in the following pages. Please refer to Appendix A for a complete list of test equipment. The test sample was operated on one of three (3) standard channels: low (906 MHz), middle (914 MHz) and high (924 MHz) to comply with FCC Part 15.31(m). The channels and operating modes were changed using a PC.

### 5.2 <u>Test Procedure</u>

Radiated RF measurements were performed on the EUT in a 3 meter Semi-Anechoic, FCC listed Chamber. The frequency range from 30 MHz to 10000 MHz was scanned and investigated. The radiated RF emission levels were manually noted at the various fixed degree settings of azimuth on the turntable and antenna height. The EUT was placed on a non-conductive pedestal in the 3 meter Semi-Anechoic Chamber, with the antenna mast placed such that the antenna was 3 meters from the EUT. A Biconical Antenna was used to measure emissions from 30 MHz to 300 MHz, and a Log Periodic Antenna was used to measure emissions from 300 MHz to 1000 MHz. A Double-Ridged Waveguide Horn Antenna was used from 1 GHz to 10 GHz. The maximum radiated RF emissions were found by raising and lowering the antenna between 1 and 4 meters in height, using both horizontal and vertical antenna polarities.

The EUT was rotated along three orthogonal axes during the investigations to find the highest emission levels. Per axis of the EUT, the EUT antennas were rotated along three orthogonal axes also. All combinations were tested to ensure the highest emissions were determined.

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### 5.3 Test Equipment Utilized

A list of the test equipment and antennas utilized for the Radiated Emissions test can be found in Appendix A. This list includes calibration information and equipment descriptions. All equipment is calibrated and used according to the operation manuals supplied by the manufacturers. All calibrations of the antennas used were performed at an N.I.S.T. traceable site. In addition, the Connecting Cables were measured for losses using a calibrated Signal Generator and an Agilent E4445A/N9039A EMI System. The resulting correction factors and the cable loss factors from these calibrations were entered into the EMI Receiver database. As a result, the data taken from the EMI Receiver accounts for the antenna correction factor as well as cable loss or other corrections, and can therefore be entered into the database as a corrected meter reading. The EMI Receiver was operated with a resolution bandwidth of 120 kHz for measurements below 1 GHz (video bandwidth of 300 kHz), and a bandwidth of 1 MHz for measurements above 1 GHz (video bandwidth of 1 MHz. From 4 GHz to 10 GHz, HP E4407B Spectrum Analyzer and Agilent E4446A Spectrum Analyzer, as well as an EMCO Horn Antenna and preamp were used.

### **Test Equipment List**

Please see Appendix A

### 5.4 Test Results

The EUT was found to **MEET** the Radiated Emissions requirements of Title 47 CFR, FCC Part 15.247 and Canada RSS-210, Issue 8 (2010), Annex 8 for a DTS transmitter. The frequencies with significant RF signal strength were recorded and plotted as shown in the Data Charts and Graphs.

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### 5.5 CALCULATION OF RADIATED EMISSIONS LIMITS

The maximum peak output power of an intentional radiator in the 2400-2483.5 MHz band, as specified in Title 47 CFR 15.247 (b)(3) and RSS 210 A8.4 is 1 Watt. The harmonic and spurious RF emissions, as measured in any 100 kHz bandwidth, as specified in 15.247 (d) and RSS 210 A8.2(b), shall be at least 20 dB below the measured power of the desired signal, and must also meet the requirements described in 15.205(c) for FCC and section 2.2,2.6 and 2.7 of RSS 210 for IC.

The following table depicts the general radiated emission limits above 30 MHz. These limits are obtained from Title 47 CFR, Part 15.209, for radiated emissions measurements. These limits were applied to any signals found in the 15.205 restricted bands. The mentioned limits correspond to those limits listed in RSS 210 section 2.7.

Frequency (MHz)	3 m Limit μV/m	3 m Limit (dBμV/m)	1 m Limit (dBµV/m)
30-88	100	40.0	-
88-216	150	43.5	-
216-960	200	46.0	-
> 960	500	54.0	63.5

Sample conversion from field strength  $\mu$ V/m to dB $\mu$ V/m: dB $\mu$ V/m = 20 log <sub>10</sub> (100) = 40 dB $\mu$ V/m (from 30-88 MHz)

For measurements made at 1.0 meter, a 9.5 dB correction has been invoked.

>960 MHz  $500\mu V/m$  or 54.0 dB/ $\mu V/m$  at 3 meters 54.0 + 9.5 = 63.5 dB/ $\mu V/m$  at 1 meter

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# RADIATED EMISSIONS TEST DATA CHART

3 Meter Measurements of Electromagnetic Radiated Emissions Test Standard: 47CFR, Part 15.205 and 15.247(DTS) RSS 210 A8, sections 2.2, 2.6 and 2.7

Frequency Range Inspected: 30 MHz to 10000 MHz

r requested residence and resi								
Manufacturer:	LS R	LS Research, LLC						
Date(s) of Test:	Marcl	n 17, 18, 21, 2011						
Test Engineer(s):	Peter	Feilen						
Voltage:	3.3 V	DC						
Operation Mode:	Pseu	do Random Bit Sequen	ce (PF	RBS)				
Environmental Conditions in the Lab:		Temperature: 20 – 25° C						
Conditions in the Lab.	Relat	ive Humidity: 30 – 60 %		1				
EUT Power:		Single PhaseVAC			3 Phase _	V	4C	
LOT FOWEI.		Battery	Battery			Other: 3.3 VDC		
EUT Placement:	X	80cm non-conductive	table		10cm Spacers			
EUT Test Location:	EUT Test Location: X 3 Meter Semi-Anechoic FCC Listed Chamber			3/10m OA	ΓS			
Measurements:		Pre-Compliance	Prelir	ninary	Х	Final		
Detectors Used:	X	Peak	Χ	Quas	i-Peak	Χ	Average	

The following table depicts the level of radiated RF fundamental emissions found:

Frequency (MHz)	Receive Antenna Polarity	EUT ANT	HT (m)	AZ (deg)	QP (dBuV/m
906.00	Н	V	1.11	0	130.58
	V	V	1.71	53	117.74
914.00	Н	V	1.07	0	130.77
	V	V	1.00	321	116.62
924.00	Н	V	1.00	13	131.31
	V	V	1.00	283	117.09

The following table depicts the level of significant spurious radiated RF emissions found:

Frequency (MHz)	Height (m)	Azimuth (degree)	Quasi Peak Reading (dBµV/m)	Quasi Peak Limit (dBμV/m)	Margin (dB)	Antenna Polarity	EUT orientation
845.0	1.00	214	44.00	46.0	2.0	V	H Board, V Ants
989.6	1.00	214	46.30	54.0	7.7	V	H Board, V Ants
828.5	1.00	0	43.15	46.0	2.9	Н	H Board, V Ants
986.4	1.00	0	45.36	54.0	8.6	Н	H Board, V Ants
38.2	1.00	0	11.47	40.0	28.5	V	H Board, V Ants
287.0	1.00	0	22.71	46.0	23.3	Н	H Board, V Ants
850.0	1.00	0	39.98	46.0	6.0	V	H Board, V Ants

Note: The spurious emissions found are not transmitter related, but rather general emissions from the EUT

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# RADIATED EMISSIONS DATA CHART (continued)

The following table depicts the level of significant radiated RF fundamental and harmonic emissions seen on Channel 1:

Frequency (MHz)	Height (m)	Azimuth (degree)	Peak Reading (dBµV/m)	Avg Reading (dBµV/m)	Avg Limit (dBμV/m)	Margin (dB)	Antenna Polarity	EUT orientation
1812	1.13	104	54.0	49.8	63.5	13.7	Horizontal	Side
2718	1	311	49.6	42.7	110.6	67.9	Horizontal	Side
3624	1	315	47.5	42.8	110.6	67.8	Vertical	Side
4530	1.02	354	53.5	46.2	63.5	17.3	Horizontal	Side
5436	1.03	331.1	52.4	44.5	93.3	48.8	Horizontal	Side
6342	1.05	98.4	46.6	35.3	110.6	75.2	Horizontal	Side
7248	1.02	93.8	51.6	40.2	74.0	33.8	Horizontal	Side
8154	1.29	124.7	58.1	48.9	120.6	71.6	Horizontal	Side
9060	1.03	27	60.1	50.6	120.6	70.0	Vertical	Side

The following table depicts the level of significant radiated RF fundamental and harmonic emissions seen on Channel 5:

Frequency (MHz)	Height (m)	Azimuth (degree)	Peak Reading (dBµV/m)	Avg Reading (dBμV/m)	Avg Limit (dBμV/m)	Margin (dB)	Antenna Polarity	EUT orientation
1828	1.3	0	52.1	48.7	63.5	14.8	Vertical	Side
2742	1.09	201	51.0	43.8	63.5	19.7	Vertical	Side
3656	1.26	0	45.7	39.8	110.8	71.0	Horizontal	Side
4570	1.02	4.3	53.6	46.1	63.5	17.4	Horizontal	Side
5484	1.03	260.5	49.4	40.1	110.8	70.7	Horizontal	Side
6398	1.1	4.7	50.3	38.3	110.8	72.5	Vertical	Side
7312	1.13	3.4	53.5	43.9	74.0	30.1	Vertical	Side
8226	1.31	85.5	58.3	49.2	120.8	71.6	Horizontal	Side
9140	1	20.2	63.5	54.5	120.8	66.2	Vertical	Side

The following table depicts the level of significant radiated RF fundamental and harmonic emissions seen on Channel 10:

Frequency (MHz)	Height (m)	Azimuth (degree)	Peak Reading (dBµV/m)	Avg Reading (dBμV/m)	Avg Limit (dBμV/m)	Margin (dB)	Antenna Polarity	EUT orientation
1848	1.52	12	55.1	51.7	63.5	11.8	Horizontal	Side
2772	1.21	0	49.5	42.9	63.5	20.6	Horizontal	Side
3696	1	320	47.4	41.8	111.3	69.5	Horizontal	Flat
4620	1.03	298.1	52.5	43.5	63.5	20.0	Horizontal	Side
5544	1.25	190.1	54.8	46.1	111.3	65.2	Vertical	Side
6468	1.13	238.4	55.5	43.4	111.3	67.9	Vertical	Side
7392	1.22	21.9	53.0	44.4	74.0	29.6	Horizontal	Side
8316	1.1	324.5	55.1	45.8	74.0	28.2	Horizontal	Side
9240	1.12	92.2	67.2	59.0	121.3	62.4	Horizontal	Side

### Notes:

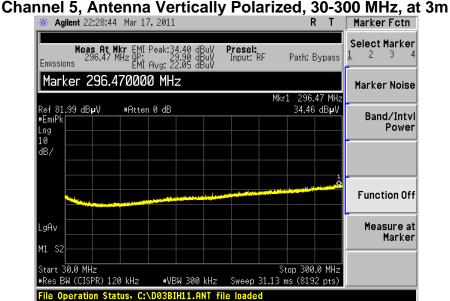
- A Quasi-Peak Detector was used in measurements below 1 GHz, and a Peak as well as an Average Detector was used in measurements above 1 GHz. The peak detector was used to ensure the peak emissions did not exceed 20 dB above the limits.
- Measurements above 4 GHz were made at 1 meters of separation from the EUT
- For measurements of the fundamental power, because of spectral bandwidth, the receiver was set to RBW=VBW=3 MHz.
- 3) 4) Various EUT board and EUT antenna positions were investigated. The above demonstrates the worst case emissions.

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### 5.7 **Screen Captures - Radiated Emissions Test**

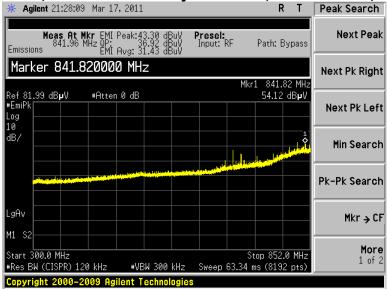
These screen captures represent Peak Emissions. For radiated emission measurements, a Quasi-Peak detector function is utilized when measuring frequencies below 1 GHz, and an Average detector function is utilized when measuring frequencies above 1 GHz.

The signature scans shown here are from worst-case emissions, as measured on channels 1, 5, or 10 with the sense antenna both in vertical and horizontal polarity for worst case presentations.





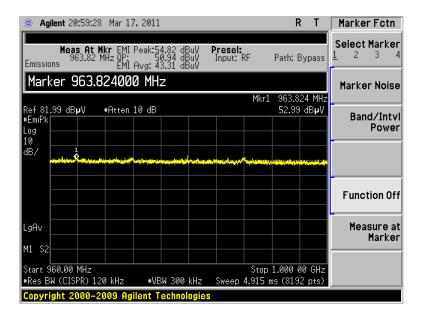
# Channel 5, Antenna Vertically Polarized, 300-852 MHz, at 3m



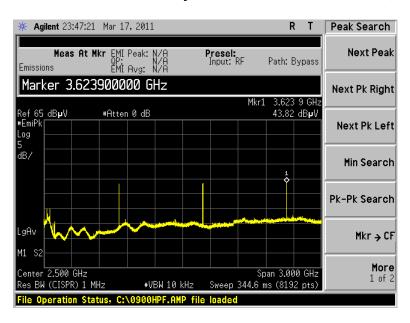
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### <u>Screen Captures - Radiated Emissions Testing</u> (continued)

### Channel 5, Antenna Vertically Polarized, 960-1000 MHz, at 3m



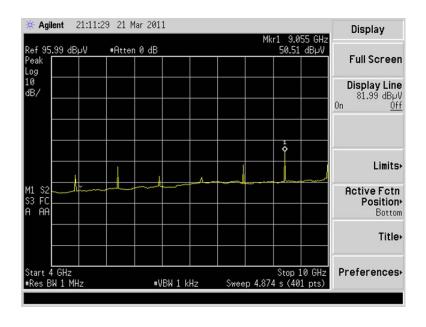
### Channel 5, Antenna Vertically Polarized, 1000-4000 MHz, at 3m



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# <u>Screen Captures - Radiated Emissions Testing</u> (continued)

# Channel 5, Antenna Vertically Polarized, 4000-10000 MHz, at 1m



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# 5.8 Receive Mode Testing

Per the requirements of RSS-210, the EUT was placed in continuous receive mode and the radiated spurious emissions were measured and compared to the limits stated in RSS-Gen Section 4.10.

The test setup, procedure, and equipment utilized were identical to that described in sections 5.1, 5.2, and 5.3 of this document.

Measurement data and screen captures from the receive tests are presented below:

Frequency (MHz)	Height (m)	Azimuth (degree)	Quasi Peak Reading (dBµV/m)	Quasi Peak Limit (dBμV/m)	Margin (dB)	Antenna Polarity	EUT orientation
298.5	1.00	0	24.09	46.0	21.9	V	TT
297.7	1.00	0	24.51	46.0	21.5	Н	TT
43.6	1.00	0	11.67	40.0	28.3	Н	TT
966.3	1.00	0	29.87	54.0	24.1	Н	TT
975.2	1.00	0	30.18	54.0	23.8	V	TT
3822.4	1.00	0	36.51	54.0	17.5	V	TT
3855.3	1.00	0	36.36	54.0	17.6	Н	TT

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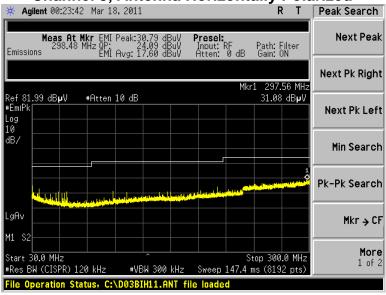
### <u>Screen Captures - Radiated Emissions Testing - Receive Mode</u>

These screen captures represent Peak Emissions. For radiated emission measurements, a Quasi-Peak detector function is utilized when measuring frequencies below 1 GHz, and an Average detector function is utilized when measuring frequencies above 1 GHz.

The signature scans shown here are from worst-case emissions, as measured on channels 1, 5 and 10, with the sense antenna both in vertical and horizontal polarity for worst case presentations.

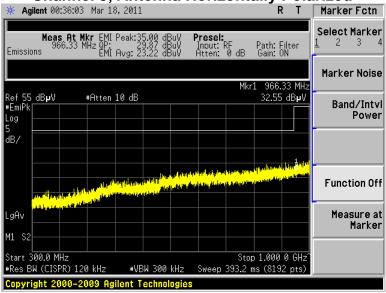
### 30-300 MHz





### 300-1000 MHz

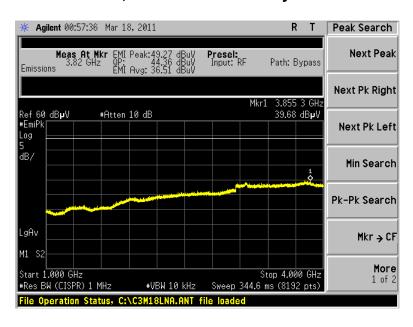
### **Channel 5, Antenna Horizontally Polarized**



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### 1000-4000 MHz

# **Channel 5, Antenna Horizontally Polarized**



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### **EXHIBIT 6. CONDUCTED EMISSIONS TEST, AC POWER LINE:**

### 6.1 Test Setup

The test area and setup are in accordance with ANSI C63.4 and with Title 47 CFR, FCC Part 15, Industry Canada RSS-210 and RSS GEN. The EUT was placed on a non-conductive wooden table, with a height of 80 cm above the reference ground plane. The EUT's power cable was plugged into a  $50\Omega$  (ohm),  $50/250~\mu$ H Line Impedance Stabilization Network (LISN). The AC power supply of 120V was provided via an appropriate broadband EMI Filter, and then to the LISN line input. Final readings were then taken and recorded. After the EUT was setup and connected to the LISN, the RF Sampling Port of the LISN was connected to a 10 dB Attenuator-Limiter, and then to the Agilent E4445A/N9039A EMI System. The EMCO LISN used has the ability to terminate the unused port with a  $50\Omega$  (ohm) load when switched to either L1 (line) or L2 (neutral).

### 6.2 Test Procedure

The EUT was investigated in continuous modulated transmit mode for this portion of the testing. The appropriate frequency range and bandwidths were selected on the EMI Receiver, and measurements were made. The bandwidth used for these measurements is 9 kHz, as specified in CISPR 16-1, Section 1, Table 1, for Quasi-Peak and Average detectors in the frequency range of 150 kHz to 30 MHz. Final readings were then taken and recorded.

### 6.3 Test Equipment Utilized

A list of the test equipment and accessories utilized for the Conducted Emissions test is provided in Appendix A. This list includes calibration information and equipment descriptions. All equipment is calibrated and used according to the operation manuals supplied by the manufacturers. Calibrations of the LISN and Limiter are traceable to N.I.S.T. All cables are calibrated and checked periodically for conformance. The emissions are measured on the Agilent E4445A/N9039A EMI System, which has automatic correction for all factors stored in memory and allows direct readings to be taken.

### **Test Equipment List**

Please see Appendix A

### 6.4 Test Results

The EUT was found to **MEET** the Conducted Emission requirements of FCC Part 15.207 Conducted Emissions for an Intentional Radiator. See the Data Charts and Graphs for more details of the test results.

### 6.5 FCC Limits of Conducted Emissions at the AC Mains Ports

Frequency Range	Class B Limits (dBµV)		Measuring
(MHz)	Quasi-Peak	Average	Bandwidth
0.150 -0.50 *	66-56	56-46	RBW = 9 kHz
0.5 - 5.0	56	46	VBW ≥ 9 kHz for QP
5.0 – 30	60	50	VBW = 1 Hz for Average
* The limit decrea			
logarithm of the fre	quency in this ra	ange.	

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# 6.6

CONDUCTED EMISSIONS TEST DATA CHART
Frequency Range inspected: 150 KHz to 30 MHz
Test Standard: FCC 15.207 Class B IC RSS GEN 7.2.2

Manufacturer:	LS	Research				
Date(s) of Test:	May	/ 12, 2011				
Test Engineer:	Pete	er Feilen				
Voltage:	3.3\	/DC				
Operation Mode:	PRE	3S				
Environmental	Ten	Temperature: 20 – 25° C				
Conditions in the Lab:	Relative Humidity: 30 – 60 %					
Test Location:		Chamber				
EUT Placed On:	Χ	40cm from Vertical Ground Plane			10cm Spacers	
EOT Flaced Off.	Χ	80cm above Ground Plane			Other:	
Measurements:		Pre-Compliance		Preliminary	Χ	Final
<b>Detectors Used:</b>	Χ	Peak	X	Quasi-Peak	Х	Average

		<u>Quasi-Peak</u>				<u>Average</u>	
Frequency (MHz)	Line	Q-Peak Reading (dBμV)	Q-Peak Limit (dBμV)	Quasi- Peak Margin (dB)	Average Reading (dBµV)	Average Limit (dBµV)	Average Margin (dB)
0.603	L1	28.600	56.000	27.400	24.900	46.000	21.100
3.999	L1	33.000	56.000	23.000	31.800	46.000	14.200
0.602	L2	27.400	56.000	28.600	23.700	46.000	22.300
4.001	L2	32.500	56.000	23.500	31.300	46.000	14.700

- 1) All other emissions were better than 20 dB below the limits.
- 2) The EUT exhibited similar emissions in transmit and receive modes, and across the Low, Middle and High channels tested.

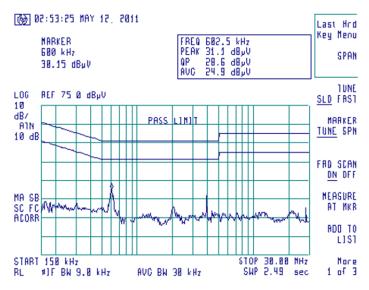
Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
Report # 311094	Model #: SiFLEX02-HP	Template: Class B DTS 10-22-09
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### 6.7 <u>Screen Captures – Conducted Emissions Test</u>

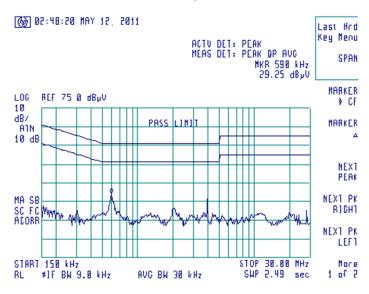
These screen captures represent Peak Emissions. For conducted emission measurements, both a Quasi-Peak detector function and an Average detector function are utilized. The emissions must meet both the Quasi-peak limit and the Average limit as described in 47 CFR 15.207 and RSS GEN 7.2.2 (Table 2).

The signature scans shown here are from channel 5 (914 MHz), chosen as being a good representative of channels.





### Line 2



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### **EXHIBIT 7.** OCCUPIED BANDWIDTH:

### 7.1 Limits

For a Digital Modulation System, the 6 dB bandwidth shall be at least 500 kHz.

### 7.2 Method of Measurements

Refer to ANSI C63.4 and FCC Procedures (2007) for Digital Transmission Systems operating under 15.247.

The transmitter output was connected to the Spectrum Analyzer. The bandwidth of the fundamental frequency was measured with the Spectrum Analyzer using 100 kHz RBW and VBW=300 kHz.

The bandwidth requirement found in FCC Part 15.247(a)(2) and RSS 210 A8.2(a) requires a minimum -6dBc occupied bandwidth of 500 kHz. In addition, Industry Canada (IC RSS GEN 4.6.1) requires the measurement of the -20dBc occupied bandwidth. For this portion of the tests, a direct measurement of the transmitted signal was performed at the antenna port of the EUT, via a cable connection to the Agilent E4446A spectrum analyzer. An attenuator of 10 dB was placed in series with the cable to protect the spectrum analyzer. The loss from the cable and the attenuator were added on the analyzer as gain offset settings, thereby allowing direct measurements, without the need for any further corrections. For 6 dB measurements, the resolution bandwidth set to 100 kHz for this portion of the tests and when 20 dB measurements were taken the resolution bandwidth set to 30 kHz for this portion of the tests. The spectrum analyzer measurement function was utilized to obtain a 20 dB and 99% occupied bandwidth measurement, as presented in the chart below. The EUT was configured to run in a pseudo random bit sequence mode, while being supplied with typical data as a modulation source.

From this data, the closest measurement (6 dB bandwidth) when compared to the specified limit, is 600 kHz, which is above the minimum of 500 kHz.

### 7.3 Test Equipment List

Test Equipment	Manufacturer	Model No.	Serial No.
Spectrum Analyzer	Agilent	E4407B	US39160256
Spectrum Analyzer	Agilent	E4446A	US45300564

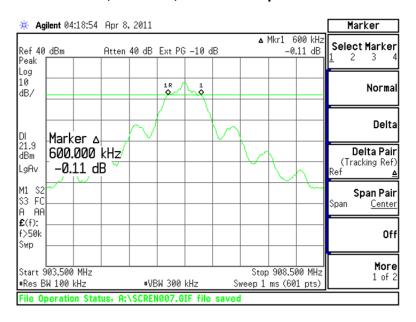
### 7.4 Test Data

Channel	Center Frequency (MHz)	Measured -6 dBc Occ. BW (kHz)	Minimum -6 dBc Limit (kHz)	Measured -20 dBc Occ.Bw (kHz)
1	906	600	500	1359
5	914	600	500	1531
10	924	600	500	1625

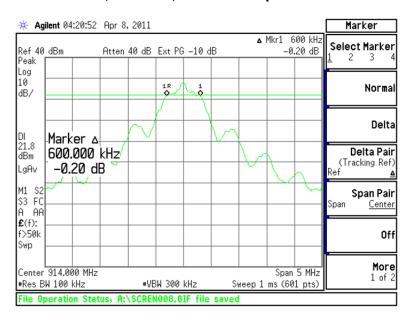
Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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### 7.5 <u>Screen Captures - OCCUPIED BANDWIDTH</u>

### Channel 1, 906 MHz, -6 dBc Occupied Bandwidth

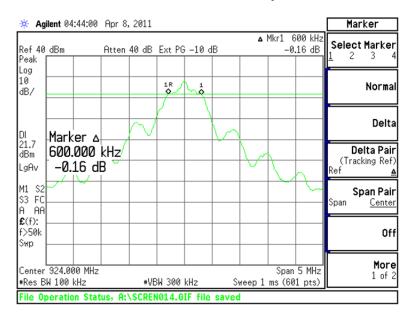


### Channel 5, 914 MHz, -6 dBc Occupied Bandwidth

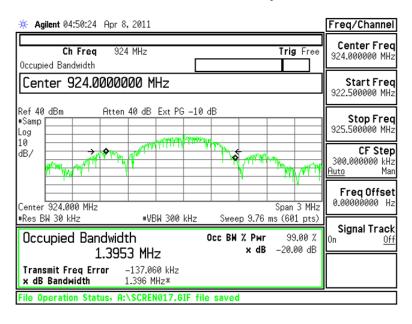


Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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### Channel 10, 924 MHz, -6 dBc Occupied Bandwidth

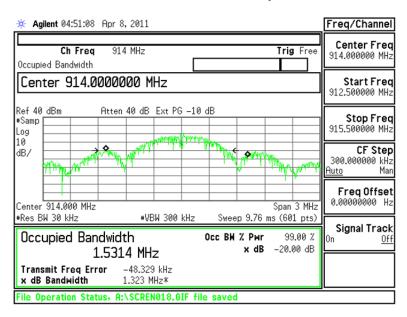


### Channel 1, 906 MHz, -20 dBc Occupied Bandwidth

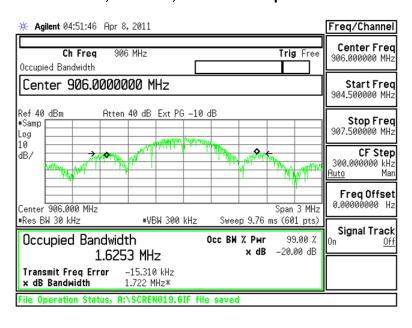


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### Channel 5, 914 MHz, -20 dBc Occupied Bandwidth



### Channel 10, 924 MHz, -20 dBc Occupied Bandwidth



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### EXHIBIT 8.BAND-EDGE MEASUREMENTS

### 8.1 Method of Measurements

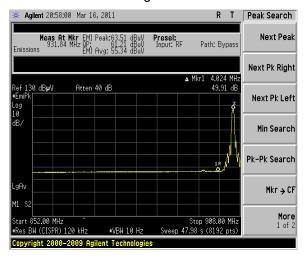
FCC 15.209(b) and 15.247(d) require a measurement of spurious emission levels to be at least 20 dB lower than the fundamental emission level, in particular at the Band-Edges where the intentional radiator operates. Also, RSS 210 Section 2.2 requires that unwanted emissions meet limits listed in tables 2 and 3 of the same standard and also to the limits in the applicable annex. The following screen captures demonstrate compliance of the intentional radiator at the 902-928 MHz Band-Edges. The EUT was operated in continuous transmit mode with continuous modulation, with internally generated data as the modulating source. The EUT was operated at the lowest channel for the investigation of the lower Band-Edge, and at the highest channel for the investigation of the higher Band-Edge.

The Lower Band-Edge limit, in this case, would be -20 dBc with respect to the fundamental level.

The Upper Band-Edge limit, in this case, would be -20 dBc with respect to the fundamental level.

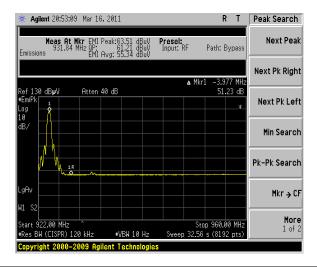
Screen Capture Demonstrating Compliance at the Lower Band-Edge.

Explanation of Result: A 49.9 dB difference from the fundamental measurement to the bandedge at 902 MHz demonstrates compliance as 49.9 dB is 29.9 dB greater than the -20 dBc necessary to be compliant



### Screen Capture Demonstrating Compliance at the Higher Band-Edge

Explanation of Result: A 51.2 dB difference from the fundamental measurement to the bandedge at 928 MHz demonstrates compliance as 51.2 dB is 31.2 dB greater than the -20 dBc necessary to be compliant



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# EXHIBIT 9. POWER OUTPUT (CONDUCTED): 15.247(b)

### 9.1 Method of Measurements

The conducted RF output power of the EUT was measured at the antenna port using a short RF cable along with an attenuator as protection for the spectrum analyzer. Any losses were added on the analyzer as gain offset settings, thereby allowing direct measurements without the need for any further corrections. The unit was configured to run in a continuous transmit mode, while being supplied with typical data from an internal modulation source. The spectrum analyzer was used with resolution and video bandwidths set to 3 MHz, and a span of 20 MHz, with measurements from a peak detector presented in the chart below.

### 9.2 Test Equipment List

Please see Appendix A

### 9.3 Test Data

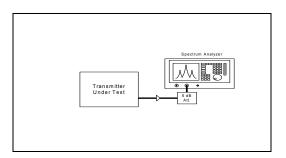
CHANNEL	CENTER FREQ (MHz)	LIMIT (dBm)	MEASURED POWER (dBm)	MARGIN (dB)
1	906	+30 dBm	28.1	1.9
5	914	+30 dBm	27.5	2.5
10	924	+30 dBm	27.0	3.0

### **Test Data**

Transmitter Channel	Freq. (MHz)	Peak Power at Antenna Terminal (dBm)	Calculated EIRP (dBm)	Conducted Power Limit (dBm)	EIRP Limit (dBm)
Lowest	2405	28.1	31.8	30.0	36.0
Middle	2445	27.5	31.2	30.0	36.0
Highest	2480	27.0	30.7	30.0	36.0

<sup>(1)</sup> EIRP Calculation:

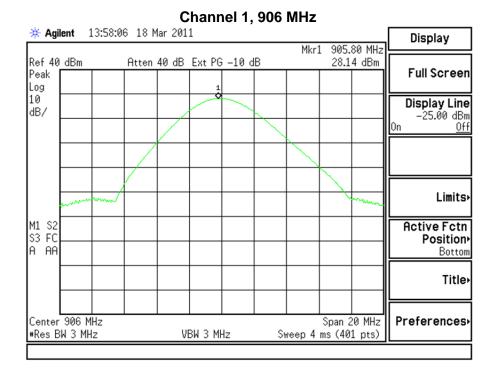
EIRP = (Peak power at antenna terminal in dBm) + (EUT Antenna gain in dBi)

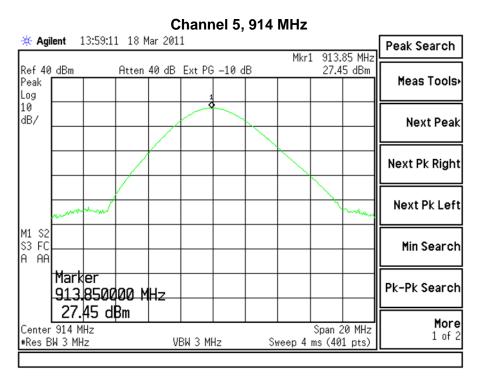


Declared RF Power Output (in Watts): 0.646 W

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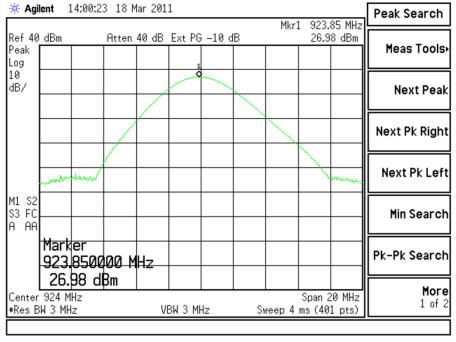
### 9.4 Screen Captures – Power Output (Conducted)





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# Channel 10, 924 MHz



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# EXHIBIT 10. POWER SPECTRAL DENSITY: 15.247(e)

### 10.1 Limits

For digitally modulate systems, the power spectral density conducted from the intentional radiator to the antenna shall not be greater than 8 dBm in any 3 kHz band during any time interval of continuous transmission.

In accordance with FCC Part 15.247(e) and RSS 210 A8.2(b), the peak power spectral density should not exceed +8 dBm in any 3 kHz band. This measurement was performed along with the conducted power output readings performed as described in previous sections. The peak output frequency for each representative frequency was scanned, with a narrow bandwidth, and reduced sweep, and a power density measurement was performed using the utility built into the HP Analyzer. The resultant density was then corrected to a 3 kHz bandwidth. The highest density was found to be no greater than 5.49 dBm, which is under the allowable limit by 2.5 dB.

### 10.2 Test Equipment List

Please see Appendix A

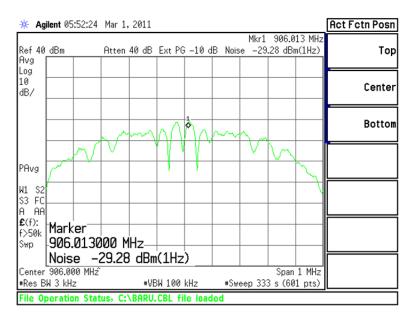
### 10.3 Test Data

Channel	Center Frequency (MHz)	Measured Channel Power (dBm/1Hz)	3 kHz Correction (dB)	Corrected Power Measurement (dBm/3kHz)	Limit (dBm)	Margin (dB)
1	906	-29.28	34.77	5.49	+8.00	2.51
5	914	-29.58	34.77	5.19	+8.00	2.81
10	924	-30.13	34.77	4.64	+8.00	3.36

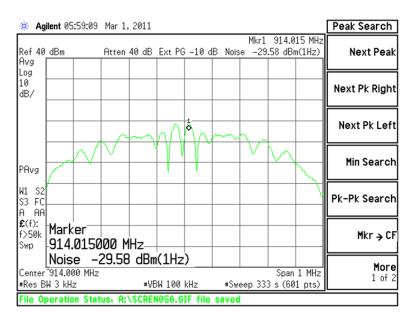
Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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### 10.4 Screen Captures – Power Spectral Density

### Channel 1

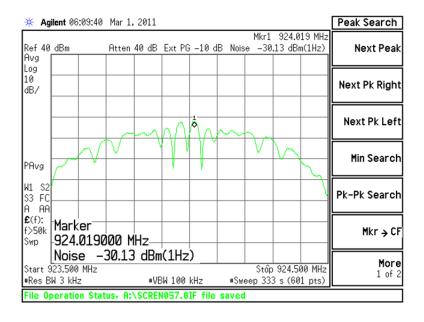


### **Channel 5**



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### **Channel 10**



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# EXHIBIT 11. SPURIOUS RADIATED EMISSIONS: 15.247(d)

### 11.1 Limits

In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at lease 20 db below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement.

In addition, radiated emissions, which fall in the restricted band, as defined in Section 15.205(a), must also comply with the radiated emission limits specified in Section 15.209(e)

### Remarks:

- Applies to harmonics/spurious emissions that fall in the restricted bands listed in Section 15.205. The maximum permitted average field strength is listed in Section 15.209.
- The emission limits as specified above are based on measurement instrument employing an average detector. The provisions in Section 15.35 for limiting peak emissions apply.

FCC 47 CFR 15.205(a) - Restricted Frequency Bands

• •	$30 \pm i \text{ OI it } 13.203(a) = itt$	conficted i requestey Dan	ius
MHz	MHz	MHz	GHz
0.090 - 0.110	162.0125 – 167.17	2310 – 2390	9.3 – 9.5
0.49 - 0.51	167.72 – 173.2	2483.5 – 2500	10.6 – 12.7
2.1735 – 2.1905	240 – 285	2655 – 2900	13.25 – 13.4
8.362 - 8.366	322 – 335.4	3260 – 3267	14.47 – 14.5
13.36 – 13.41	399.9 – 410	3332 – 3339	14.35 – 16.2
25.5 – 25.67	608 – 614	3345.8 – 3358	17.7 – 21.4
37.5 – 38.25	960 – 1240	3600 – 4400	22.01 – 23.12
73 – 75.4	1300 – 1427	4500 – 5250	23.6 – 24.0
108 – 121.94	1435 – 1626.5	5350 – 5460	31.2 – 31.8
123 – 138	1660 – 1710	7250 – 7750	36.43 – 36.5
149.9 – 150.05	1718.8 – 1722.2	8025 – 8500	Above 38.6
156.7 – 156.9	2200 – 2300	9000 – 9200	

FCC 47 CFR 15.209(a) Field Strength Limits within Restricted Frequency Bands

Frequency (MHz)	Field Strength Limits (microvolts/m)	Distance (Meters)
0.009 - 0.490	2,400 / F (kHz)	300
0.490 - 1.705	24,000 / F (kHz)	30
1.705 – 30.0	30	30
30 – 88	100	3
88 – 216	150	3
216 – 960	200	3
Above 960	500	3

### **Calculation of Radiated Emission Measurements**

Frequency (MHz)	3 m Limit (μV/m)	3 m Limit (dBμV/m)	1 m Limit (dBµV/m)
30-88	100	40.0	-
88-216	150	43.5	-
216-960	200	46.0	-
960-25,000	500	54.0	63.5

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FCC Part 15.247(d) and IC RSS 210 A8.5 requires a measurement of conducted harmonic and spurious RF emission levels, as reference to the carrier level when measured in a 100 kHz bandwidth. For this test, the spurious and harmonic RF emissions from the EUT were measured at the EUT antenna port using a short RF cable along with an attenuator as protection for the spectrum analyzer. Any losses from the cabling and the attenuator were added on the analyzer as gain offset settings, there by allowing direct readings of the measurements made without the need for any further corrections. An Agilent E4446A spectrum analyzer was used with the resolution bandwidth set to 100 kHz for this portion of the tests. The unit was configured to run in a continuous transmit mode, while being supplied with typical data as a modulation source. The spectrum analyzer was used with measurements from a peak detector presented in the chart below. Screen captures were acquired and any noticeable spurious and harmonic signals were identified and measured. No significant emissions could be noted within -34 dBc of the fundamental level for this product.

### 11.2 Test Equipment List

Please see Appendix A

# 11.3 Test Data Conducted Harmonic Emissions

Freq\Chan	906	914	924
fo	28.1	27.5	27.0
2fo	-16.0	-16.9	-18.6
3fo	-7.0	-6.9	-7.5
4fo	-68.8	-69.3	-72.0
5fo	-70.4	-70.3	-74.5
6fo	-69.4	-68.4	-71.3
7fo	-68.9	-72.6	-72.0
8fo	-72.3	69.5	-67.2
9fo	-63.6	-65.3	-66.4
10fo	-67.2	-66.5	-67.9

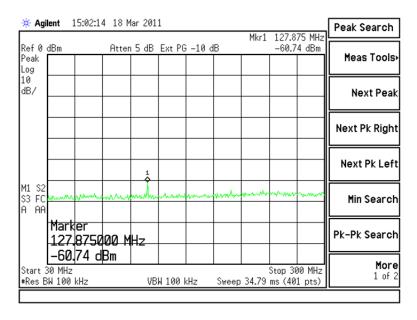
### **Extra Spurious Conducted Emissions**

Freq(MHz)	Chan	level(dBm)	limit (dBm)	Margin (dB)
157.58	10	-58.4	7	65.4
900.50	10	-44.7	7	51.7
716.90	10	-49.6	7	56.6
474.60	10	-60.1	7	67.1
349.70	10	-55.0	7	62.0
931.78	10	-28.5	7	35.5
940.24	10	-41.6	7	48.6
948.34	10	-47.2	7	54.2
987.94	10	-50.8	7	57.8
929.62	5	-41.5	7.5	49.0
900.50	5	-38.5	7.5	46.0
706.35	5	-50.8	7.5	58.3
384.30	5	-57.2	7.5	64.7
325.58	5	-54.1	7.5	61.6
127.88	5	-58.3	7.5	65.8
103.58	1	-58.5	8.1	66.6
895.98	1	-19.3	8.1	27.4
929.62	1	-46.1	8.1	54.2
937.72	1	-49.0	8.1	57.1
969.94	1	-51.6	8.1	59.7
985.96	1	-51.6	8.1	59.7

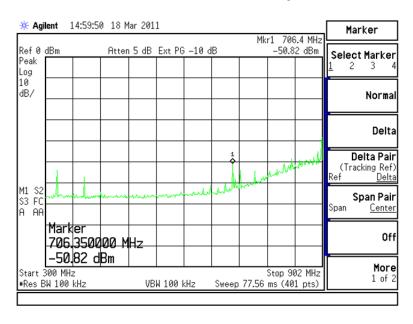
Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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### 11.4 Screen Captures – Spurious Radiated Emissions

### Channel 5, shown from 30 MHz up to 300 MHz

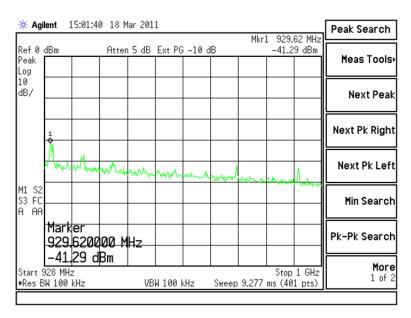


# Channel 5, shown from 300 MHz up to 902 MHz

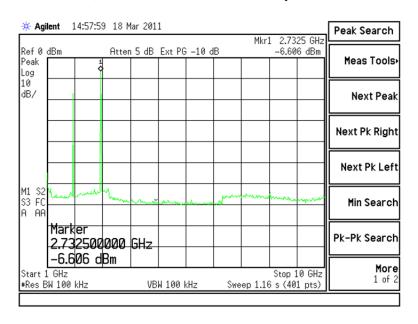


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# Channel 5, shown from 928 MHz up to 1000 MHz



# Channel 5, shown from 1000 MHz up to 10000 MHz



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### **EXHIBIT 12. FREQUENCY & POWER STABILITY OVER VOLTAGE VARIATIONS**

The stability of the device was examined as a function of the input voltage available to the EUT. A Spectrum Analyzer was used to measure the frequency at the appropriate frequency markers. Power was supplied by an external bench-type variable power supply, and the frequency of operation was monitored using the spectrum analyzer

A spectrum analyzer was used to measure the frequency at the appropriate frequency markers. For this test, the EUT was placed in continuous transmit CW mode. Power to the EUT was supplied by an external bench-type variable power supply. The frequency of operation was monitored using the spectrum analyzer with RBW=VBW=1 kHz settings while the voltage was varied.

The RF Power Output of the EUT was also monitored in a separate test, also using a Spectrum Analyzer with RBW=VBW=3 MHz setting while the voltage was varied.

The power was then cycled On/Off to observe system response. No unusual response was observed, the emission characterizes were well behaved, and the system returned to the same state of operation as before the power cycle.

At the extreme temperature settings, a wide frequency sweep was also investigated, with minimum and maximum input voltages, to ensure that no unexpected anomalies have occurred.

No anomalies were noted in the measured transmit power, varying less than 0.8 dB, during the voltage variation tests.

### **Power Stability**

4.0 VDC		4.5 VDC	
Power	Frequency	Power	Frequency
27.69	905.969600	28.27	906.027000
28.03	913.967000	28.34	913.977000
27.54	923.977000	28.05	924.020000

A nominal voltage of 4.0 VDC and the manufacturer's stated maximum of 4.5 VDC was used in determining the output power stability and to ensure the maximum output power limitation was not exceeded.

### Frequency Stability

3.4 VDC	4.0 VDC	4.5 VDC
Frequency	Frequency	Frequency
905.967000	905.969600	906.027000
913.983000	913.967000	913.977000
924.027000	923.977000	924.020000

A nominal voltage of 4.0 VDC, as well as a voltage lesser than the nominal voltage by 15% and greater than the nominal voltage of the manufacturer's stated maximum of 4.5 VDC was used in determining if frequency stability requirements were met.

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# **APPENDIX A**



	te : 11-May-2011		Type Test	: Conducted AC	Emissions		_ Job#	: C-1148
Prepared	By: Peter		Customer:	LSR			Quote #	: 311094
Prepared	by: Peter		_ Customer:	LOR			_ Quote #	311094
Asset#	Description		Manufacturer	Model#	Serial#	Cal Date	Cal Due Date	Equipment Status
AA 960008			EMCO	3816/2NM	9701-1057	1/4/2011	1/4/2012	Active Calibration
EE 960013			HP	8546A System	3617A00320;3448A		10/29/2011	Active Calibration
EE 960014			HP	85460A	3448A00296	10/29/2010	10/29/2011	Active Calibration
AA 960031	Transient Limiter		HP	11947A	3107A01708	9/28/2010	9/28/2011	Active Calibration
		Project Engineer:	leter Files	,	0	uality Assurance	. Hupol	
LS F	RESEARCH LLC less Product Development quipment Calibration							
Da	te : 25-Mar-2011		Type Test	: Spurious Emiss	sions		Job#	: <u>C-1148</u>
Prepared	Ву:		Customer:	LSR			Quote #	311094
	Bara adallar				0-1-14	0.18-1-	0.188	le de la constante
Asset#	Description		Manufacturer	Model#	Serial#	Cal Date	Cal Due Date	Equipment Status
AA 960144 EE 960073	Phaseflex Spectrum Analyzer		Gore Agilent	EKD01D010720 E4446A	5800373 US45300564	6/4/2010 9/22/2010	6/4/2011 9/22/2011	Active Calibration Active Calibration
	ess Product Development juipment Calibration te : 25-Mar-2011		Type Test	: Power Spectral	Density		_ Job#	: <u>C-1148</u>
Prepared	By: Peter		Customer:	LSR			Quote #	: 311094
Asset #	Description		Manufacturer	Model#	Serial#	Cal Date	Cal Due Date	Equipment Status
AA 960144	Phaseflex		Gore	EKD01D010720	5800373	6/4/2010	6/4/2011	Active Calibration
EE 960073	Spectrum Analyzer		Agilent	E4446A	US45300564	9/22/2010	9/22/2011	Active Calibration
		Project Engineer:	leter Feilen	,	0	uality Assurance	Shipsel	
LS F	RESEARCH LLC less Product Development juipment Calibration							
Wirel Ec	uipment Calibration							
	uipment Calibration		Type Test	: Conducted Pow	er Output		Job#	: <u>C-1148</u>
	ite : 25-Mar-2011		Type Test Customer:		er Output			: <u>C-1148</u>
Da Prepared	ite : 25-Mar-2011				ser Output	Cal Date		
Prepared  Asset #  AA 960144	tte: 25-Mar-2011 By:		Customer:	LSR	Serial # 5800373		Quote # Cal Due Date 6/4/2011	: 311094
Prepared  Asset #  AA 960144	te: 25-Mar-2011  By:  Description		Customer:	LSR Model#	Serial#	Cal Date	Quote #	Equipment Status
Da Prepared Asset#	te : 25-Mar-2011  By:  Description  Phaseflex		Customer:	LSR Model# EKD01D010720	Serial # 5800373 US45300564	Cal Date 6/4/2010 9/22/2010	Quote # Cal Due Date 6/4/2011	Equipment Status Active Calibration Active Calibration

Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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 Date: 25-Mar-2011
 Type Test: Occupied Bandwidth (6dB & 2ddB)
 Job # : C-1148

 ared By:
 Customer: LSR
 Quote #: 311094

 No.
 Asset #
 Description
 Manufacturer
 Model #
 Serial #
 Cal Date
 Cal Due Date
 Equipment Status

 1
 AA 960144
 Phaseflex
 Gore
 EKD01D010720
 5800373
 6/4/2010
 6/4/2011
 Active Calibration

 2
 EE 960073
 Spectrum Analyzer
 Aglient
 E446A
 US45300564
 9/22/2010
 9/22/2011
 Active Calibration

Project Engineer: Lette Files Quality Assurance:

LS RESEARCH LLC
Wireless Product Development
Equipment Calibration

 Date:
 25-Mar-2011
 Type Test:
 Band-Edge
 Job #:
 C-1148

 Prepared By: Peter
 Customer: LSR
 Quote #: 311094

Serial# Cal Date No. Asset# Description Manufacturer Cal Due Date Equipment Status AA 960078 Log Periodic Antenna 93146 9701-4855 10/19/2010 10/19/2011 Active Calibration EE 960156 100kHz-1GHz Analog Signal Generator MY49060062 6/7/2010 6/7/2011 N5181A Active Calibration Agilent 3Hz-13.2GHz Spectrum Analyzer RF Preselecter Active Calibration Active Calibration EE 960157 E4445A MY48250225 6/7/2010 6/7/2011 EE 960158 MY46520110 6/7/2010 N9039A 6/7/2011 Agilent

Project Engineer: lette Fishen Quality Assurance:

LS RESEARCH LLC
Wireless Product Development
Equipment Calibration

 Date:
 25-Mar-2011
 Type Test:
 Radiated Emissions
 Job #: C-1148

 Prepared By: Peter
 Customer: LSR
 Quote #: 311094

No. Asset# Description Manufacturer Model# Serial# Cal Date Cal Due Date Equipment Status 1 EE 960156 100kHz-1GHz Analog Signal Generator MY49060062 Agilent N5181A 6/7/2010 6/7/2011 Active Calibration EE 960157 3Hz-13.2GHz Spectrum Analyzer Agilent E4445A MY48250225 6/7/2010 6/7/2011 MY46520110 6/7/2010 EE 960158 RF Preselecter Agilent N9039A 6/7/2011 Active Calibration Log Periodic Antenna 10/19/2010 Active Calibration AA 960150 Bicon Antenna ETS 3110B 0003-3346 10/19/2010 10/19/2011 Active Calibration AA 960081 Double Ridge Horn Antenna EMCO 3115 1/4/2011 1/4/2012 Active Calibration EE 960159 0.8 - 21GHz LNA Mini-Circuits ZVA-213X-S+ 740411007 8/19/2010 8/19/2011 Active Calibration AA 960158 Double Ridge Horn Antenna 3117 EMCO 109300 8/19/2010 8/19/2011 Active Calibration

Project Engineer: Lette Files Quality Assurance:

Prepared For: LS Research, LLC	EUT: SiFlex-02 HP	LS Research, LLC
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# <u>APPENDIX B</u> <u>TEST STANDARDS – CURRENT PUBLICATION DATES RADIO</u>

	SISIAN		CORREI
STANDARD#	DATE	Am. 1	Am. 2
ANSI C63.4	2003		
ANSI C63.10	2009		
CISPR 11	2009-05	2009-12 P	
CISPR 12	2007-05		
CISPR 14-1	2005-11	2008-11	
CISPR 14-2	2001-11	2001-11	2008-05
CISPR 16-1-1 Note 1	2010-01		
CISPR 16-1-2 Note 1	2003	2004-04	2006-07
CISPR 22	2008-09		
CISPR 24	1997-09	2001-07	2002-10
EN 55011	2007-05		
EN 55014-1	2006		
EN 55014-2	1997		
EN 55022	2006	2007	
EN 60601-1-2	2007-03		
EN 61000-3-2	2006-05		
EN 61000-3-3	2008-12		
EN 61000-4-2	2009-05		
EN 61000-4-3	2006-07	2008-05	
EN 61000-4-4	2004		
EN 61000-4-5	2006-12		
EN 61000-4-6	2009-05		
EN 61000-4-8	1994	2001	
EN 61000-4-11	2004-10		
EN 61000-6-1	2007-02		
EN 61000-6-2	2005-12		
EN 61000-6-3	2007-02		
EN 61000-6-4	2007-02		
FCC 47 CFR, Parts 0-15,	2000		
18, 90, 95 FCC Public Notice DA 00-	2008		
1407	2000		
FCC ET Docket # 99-231	2002		
FCC Procedures	2007		
ICES 001	2006-06		
ICES 002	2009-08		
ICES 003	2004-02		
IEC 60601-1-2 Note 1	2007-03		
IEC 61000-3-2	2005-11	2008-03	2009-02
IEC 61000-3-3	2008-06		
IEC 61000-4-2	2008-12		
IEC 61000-4-3	2008-04	incl in 2008-04	2009-12 FD

SLICATION DATES	INADIO		
STANDARD#	DATE	Am. 1	Am. 2
IEC 61000-4-4	2004-07	2010-10	
IEC 61000-4-5	2005-11		
IEC 61000-4-6	2008-10		
IEC 61000-4-8	2009-09		
IEC 61000-4-11	2004-03		
IEC 61000-6-1	2005-03		
IEC 61326-1	2006-06		
ISO 14982	1998-07		
MIL Std. 461E	1999-08		
RSS GEN	2010-12		
RSS 119	2007-06		
RSS 123	1999-11		
RSS 125	2000-03		
RSS 131	2003-07		
RSS 136	2002-10		
RSS 137	2009-02		
RSS 210	2010-12		
RSS 213	2005-12		
RSS 243	2005-11		
RSS 310	2007-06		
Note 1. Test not on LCD	Scope of Ace	araditation	1

Note 1: Test not on LSR Scope of Accreditation.

Updated on 02-03-10
P=Project FD= Final Draft

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### APPENDIX C Uncertainty Statement

This uncertainty represents an expanded uncertainty expressed at approximately the 95 % confidence level, using a coverage factor of k=2.

Table of Expanded Uncertainty Values, (K=2) for Specified Measurements

Measurement Type	Particular Configuration	Uncertainty Values
Radiated Emissions	3 – Meter chamber, Biconical Antenna	4.24 dB
Radiated Emissions	3-Meter Chamber, Log Periodic Antenna	4.8 dB
Radiated Emissions	10-Meter OATS, Biconical Antenna	4.18 dB
Radiated Emissions	10-Meter OATS, Log Periodic Antenna	3.92 dB
Conducted Emissions	Shielded Room/EMCO LISN	1.60 dB
Radiated Immunity	3 Volts/Meter in 3-Meter Chamber	1.128 Volts/Meter
Conducted Immunity	3 Volts level	1.0 V

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